2SC3979, 2SC3979A

Silicon NPN triple diffusion planar type

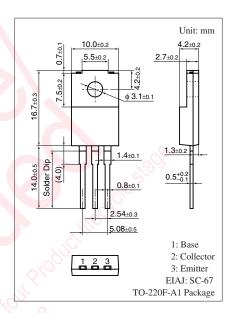
For high breakdown voltage high-speed switching

■ Features

- High-speed switching
- ullet High collector-base voltage (Emitter open) V_{CBO}
- Wide safe operation area
- Satisfactory linearity of forward current transfer ratio h_{FE}
- Full-pack package which can be installed to the heat sink with one screw

■ Absolute Maximum Ratings $T_C = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Collector-base voltage	2SC3979	V _{CBO}	900	V
(Emitter open)	2SC3979A		1 000	
Collector-emitter voltage	2SC3979	V _{CES}	900	V
(E-B short)	2SC3979A		1 000	
Collector-emitter voltage	V _{CEO}	800	V	
Emitter-base voltage (Col	V _{EBO}	7	V	
Base current	I_{B}	1	A	
Collector current	I_{C}	3	Α	
Peak collector current	I_{CP}	5	A	
Collector power	P _C	40	W	
dissipation	$T_a = 25^{\circ}C$		2.0	
Junction temperature	T_{j}	150	°C	
Storage temperature		T _{stg}	-55 to +150	°C



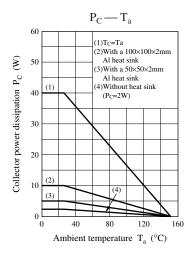
■ Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

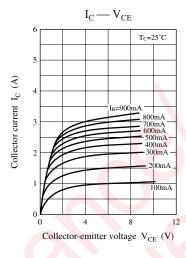
Parameter		Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)		V_{CEO}	$I_C = 10 \text{ mA}, I_B = 0$	800			V
Collector-base cut-off current 2	2SC3979	I_{CBO}	$V_{CB} = 900 \text{ V}, I_E = 0$			50	μΑ
(Emitter open)	2SC3979A		$V_{CB} = 1000 \text{ V}, I_E = 0$			50	
Emitter-base cutoff current (Collector open)		I_{EBO}	$V_{EB} = 7 \text{ V}, I_C = 0$			50	μΑ
Forward current transfer ratio		$h_{\rm FE1}$	$V_{CE} = 5 \text{ V}, I_{C} = 0.1 \text{ A}$	8			_
		$h_{\rm FE2}$	$V_{CE} = 5 \text{ V}, I_{C} = 0.8 \text{ A}$	6			
Collector-emitter saturation vo	oltage	$V_{\text{CE}(\text{sat})}$	$I_C = 0.8 \text{ A}, I_B = 0.16 \text{ A}$			1.5	V
Base-emitter saturation voltage	ge	$V_{BE(sat)}$	$I_C = 0.8 \text{ A}, I_B = 0.16 \text{ A}$			1.5	V
Transition frequency		f_T	$V_{CE} = 5 \text{ V}, I_{C} = 0.15 \text{ A}, f = 1 \text{ MHz}$		10		MHz
Turn-on time		t _{on}	$I_C = 0.8 \text{ A}$			0.7	μs
Storage time		t _{stg}	$I_{B1} = 0.16 \text{ A}, I_{B2} = -0.32 \text{ A}$			2.5	μs
Fall time		$t_{\rm f}$	$V_{CC} = 250 \text{ V}$			0.3	μs

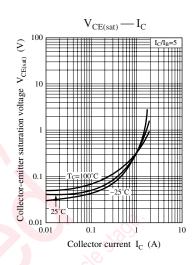
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

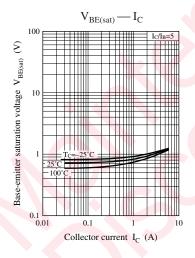
Publication date: February 2003 SJD00122BED 1

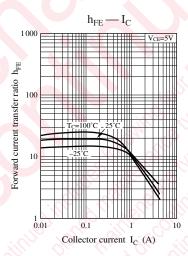
Panasonic

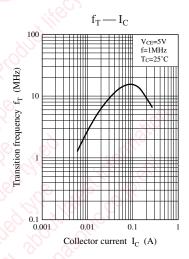


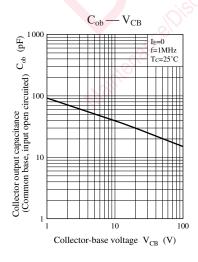


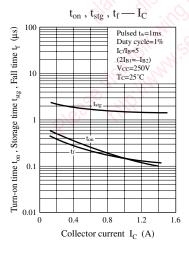


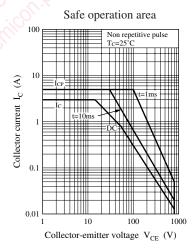






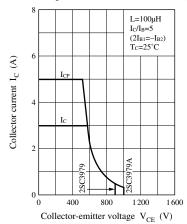




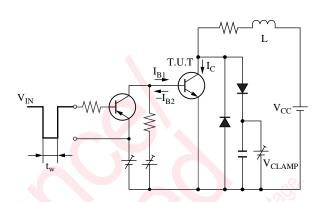


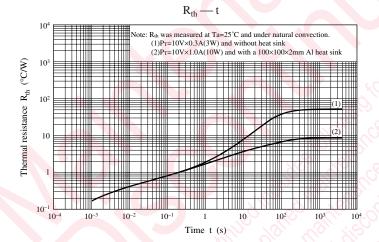
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Safe operation area (Reverse bias)



Safe operation area (Reverse bias) measurement circuit





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